

21 – 32 GHz Medium Power Amplifier

ADH499S

1.0 SCOPE

This specification documents the detail requirements for an internally defined equivalent flow per MIL-PRF-38535 Class V except as modified herein.

The manufacturing flow described in the RF & MICROWAVE STANDARD SPACE LEVEL PRODUCTS PROGRAM brochure is to be considered a part of this specification.

This data specifically details the space grade version of this product. A more detailed operational description and a complete data sheet for commercial product grades can be found at http://www.analog.com/HMC499

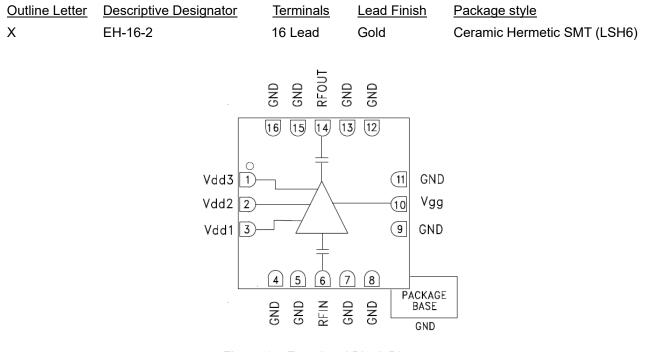
2.0 Part Number

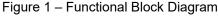
The complete part number(s) of this specification follows:

Specific Part Number	Description
ADH499-701LSH6	21 – 32 GHz GaAs PHEMT MMIC Medium Power Amplifier

3.0 Case Outline

The case outline(s) are as designated in MIL-STD-1835 and as follows:





Package: X

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Pin Number	Terminal Symbol	Pin Type	Pin Description	Interface Schematic
1	Vdd3	Power		⊖Vdd1,2,3
2	Vdd2	Power	Power Supply Voltages for the amplifier. External bypass capacitors of 100 pF, 1000 pF, and 2.2 μF are required.	
3	Vdd1	Power		'
4	GND	Power	Signal/Supply ground	GND
5	GND	Power	Signal/Supply ground	<u> </u>
6	RFIN	RF I/O	This pin is AC coupled and matched to 50 Ohms.	
7	GND	Power	Signal/Supply ground	OGND
8	GND	Power	Signal/Supply ground	
9	GND	Power	Signal/Supply ground	<u> </u>
10	Vgg	Power	Gate control for the amplifier. Adjust to achieve ldd of 200 mA External bypass capacitors of 100 pF, 1000 pF and 2.2 µF are required.	vgg
11	GND	Power	Signal/Supply ground	○ GND
12	GND	Power	Signal/Supply ground	0.1.5
13	GND	Power	Signal/Supply ground	4
14	RF OUT	RF I/O	This pin is AC coupled and matched to 50 Ohms.	
15	GND	Power	Signal/Supply ground	
16	GND	Power	Signal/Supply ground	
Package Bottom	GND	Power	Signal/Supply ground $^{1/}$	
Package Lid	GND	Power	Signal/Supply ground ^{2/}	=

Figure 2 – Terminal Connections

 $\underline{1}/$ Package bottom ground paddle must be connected to Signal/Supply ground $\underline{2}/$ Package lid is internally connected to Signal/Supply ground

4.0 Specifications

4.1.	<u>Absolute Maximum Ratings 1</u> /	
	Drain Bias Voltage (Vdd1, Vdd2, Vdd3)	+5.5 Vdc
	Gate Bias Voltage (Vgg)	-4 V to 0 Vdc
	RF Input Power (RFIN) (Vdd1, Vdd2, Vdd3 = +5 Vdc)	+20 dBm
	Thermal resistance (Channel to Package bottom)	
	Continuous Pdiss (T _A = +85°C) (Derate 25 mW/°C above +85 °C)	1.0 W
	Maximum Junction Temperature	+175 °C
	Storage Temperature range	
	ESD Sensitivity (HBM)	Class 0
4.2.	Recommended Operating Conditions	
	Operating Temperature	-40 °C to +85 °C
	Supply Voltage (Vdd1, Vdd2, Vdd3)	+5 Vdc
4.3.	Nominal Operating Performance Characteristics 2/	
	Input Return Loss (S11) (21-24 GHz)	10 dB
	Input Return Loss (S11) (24-28 GHz)	8 dB
	Input Return Loss (S11) (28-32 GHz)	8 dB
	Output Return Loss (S22) (21-24 GHz)	11 dB
	Output Return Loss (S22) (24-28 GHz)	12 dB
	Output Return Loss (S22) (28-32 GHz)	8 dB
	Saturated Output Power (Psat) (21-24 GHz)	23.5 dBm
	Saturated Output Power (Psat) (24-28 GHz)	23.5 dBm
	Saturated Output Power (Psat) (28-32 GHz)	24 dBm

1/ Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions outside of those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability. 2/ All typical specifications are at T_A = 25°C, Vdd1, Vdd2, Vdd3= 5V, Idd = 200mA unless otherwise noted. 3/ Psat specified as OP5dB.

Parameter See notes at end of table	Symbol	AL PERFORMANCE CHARACTE Conditions <u>1</u> / Unless otherwise specified	Sub- Group	Limit Min	Limit Max	Units
Supply Current	IDD	Vgg = -0.8 V typical	1, 2, 3		225	mA
		21 GHz	4	14		dB
			5	12.2		
			6	14		
			4	13		
Gain	S21	28 GHz	5	11.2		dB
			6	13		1
			4	9		
		32 GHz	5	7.2		dB
			6	9		
Gain Variation over Temperature 2/	A _v /°C	21 GHz, 28 GHz, 32 GHz	4, 5, 6		0.04	dB/°C
		21 GHz	4		8	dB dB
	NF		5		9	
			6		7.5	
		28 GHz	4		4.5	
Noise Figure			5		5.5	
			6		4	
		32 GHz	4		6	
			5		7	dB
			6		5	
		21GHz	4, 5, 6	24		
Output Power for 1dB Compression 2/	OP1dB	28 GHz	4, 5, 6	22.5		dBm
		32 GHz	4, 5, 6	21.5		7
		21 GHz	4, 5, 6	28		dBm
Output Third Order Intercept 2/3/	OIP3	28 GHz	4, 5, 6	31		dBm
		32 GHz	4, 5, 6	30		dBm

TABLE IA NOTES:

 $1/T_A$ nom = +25 °C, T_A max = +85 °C, T_A min = -40 °C, Vdd1 = Vdd2 = Vdd3 = 5V, Idd = 200mA (Adjust Vgg between -2V to 0V to achieve Idd = 200mA). $2/P_A$ Parameter is part of device initial characterization which is only repeated after design and process changes or with subsequent wafer lots. $3/R_FOUT = 0$ dBm per tone. 1 MHz spacing.

Test Requirements	Subgroups (in accordance with MIL-PRF-38535, Table III)
Interim Electrical Parameters	1, 4
Final Electrical Parameters	1,4 <u>1/ 2</u> /
Group A Test Requirements	1, 2, 3, 4, 5, 6
Group C end-point electrical parameters	1,4 <u>2</u> /
Group D end-point electrical parameters	1,4

TABLE IIA – ELECTRICAL TEST REQUIREMENTS

Table IIA Notes:

<u>1</u>/ PDA applies to Table I subgroup 1 and Table IIB delta parameters. <u>2</u>/ See Table IIB for delta parameters

Parameter	Symbol	Delta	Units
Gain at 21 GHz	S21	±1.0	dB
Gain at 24 GHz	S21	±1.0	dB
Gain at 28 GHz	S21	±1.0	dB
Supply Current	IDD	±10	%

TABLE IIB – BURN-IN/ LIFE TEST DELTA LIMITS 1/2/3/

 $\underline{1}/240$ hour burn in and 1000 hour life test (Group C) end point electrical parameters. $\underline{2}/$ Deltas are performed at T_A = +25°C only. $\underline{3}/$ Vgg voltage set to pre burn-in value for each device

5.0 Burn-In Life Test,

- 5.1. Burn-In Test Circuit, Life Test Circuit
 - 5.1.1. The test conditions and circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 test condition B of MIL –STD-883.
 - 5.1.2.HTRB is not applicable for this drawing.

6.0 MIL-PRF-38535 QMLV Exceptions

The manufacturing flow described in the RF & MICROWAVE STANDARD SPACE LEVEL PRODUCTS PROGRAM is to be considered a part of this specification. The brochure describes standard QMLV exceptions for Aerospace products run at the ADI Chelmsford, MA facility

6.1. Wafer Fabrication

Foundry information is available upon request.

6.2. Group D

Group D-5 Salt Atmosphere testing is not performed.

7.0 Application Notes

Component	Value
C1	100pf
C2	1000 pf
C3	2.2 µf

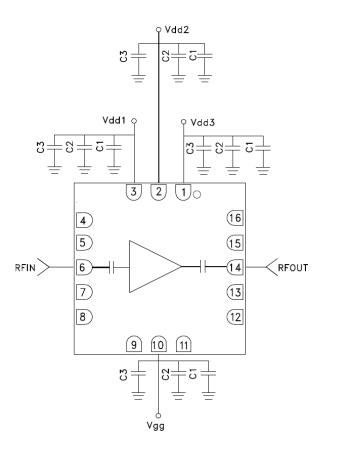


Figure 3 – Application Circuit

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8.0 Package Outline Dimensions

The LSH6 package and outline dimensions can be found at <u>http://www.analog.com</u> or upon request.

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADH499-701LSH6	–40° C to +85 °C	16 Lead Ceramic Leadless SMT	LSH6 (EH-16-2)

	Revision History			
Rev	Description of Change	Date		
А	Initial Release	3/20/2023		

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